

CONNECTION DIAGRAM
(top view)

T-52-13-45

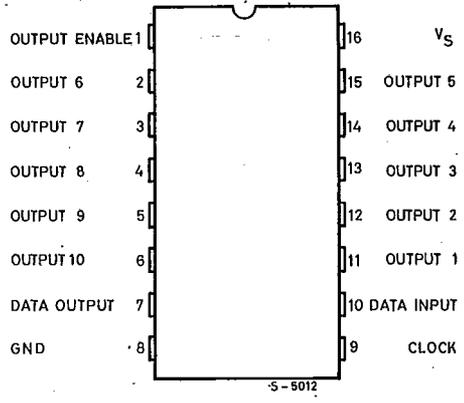
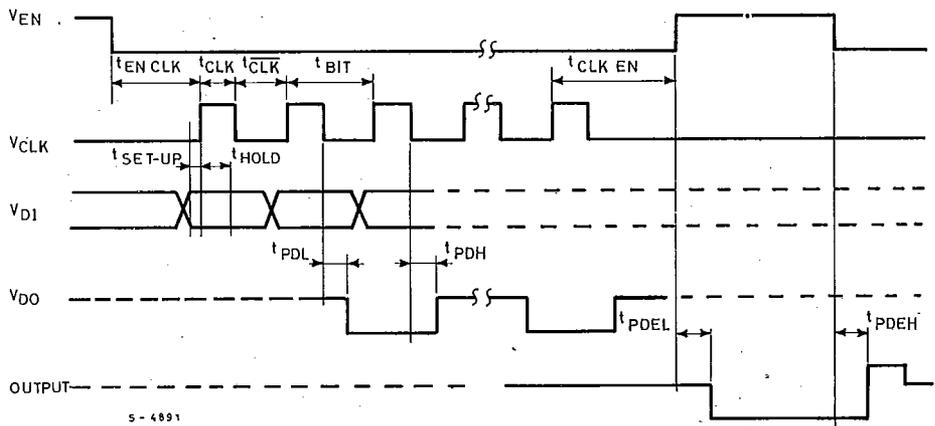


Fig. 1 - Timing diagram



THERMAL DATA

$R_{th\ j-amb}$	Thermal resistance junction-ambient	max 80 °C/W
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T-52-13-45

ELECTRICAL CHARACTERISTICS ($V_s = 5V$, $V_E = 30V$, $T_{amb} = 0^\circ$ to $70^\circ C$, unless otherwise specified)

Parameter	Test conditions	Min.	Typ.	Max.	Unit	
V_s Supply voltage		4.75		9.5	V	
I_s Supply current	$T_{amb} = 25^\circ C$ $V_s = 9.5V$	$V_{EN} = 0V$; $V_{DO} = 0V$		27	40	mA
		$V_{EN} = 2.6V$ $I_o = 250$ mA (each bit)		55	70	mA
V_E External operating supply voltage				40	V	
I_{leak} Output leakage current (each output)	$V_E = 40V$ $V_{EN} = 0V$			1	mA	
V_Z Internal clamp voltage	$I_z = 0.3A$ * $V_{EN} = 0V$	45	50	65	V	
$V_{CE sat}$ Output saturation voltage	$I_o = 250$ mA $V_{EN} = 2.6V$			1.6	V	
V_{DI} Input logic levels (pins 1, 9, 10) V_{CLK} V_{EN}	Low State (L)			0.8	V	
	High state (H)	2.6				
I_{DI} Data input current	$V_{DI} = 2.6V$	$T_{amb} = 70^\circ C$	0.3	0.57	mA	
		$T_{amb} = 0^\circ C$		0.57		0.75
	$V_{DI} = 1V$	$T_{amb} = 70^\circ C$		220	μA	
I_{CLK} Clock input current	$V_{CLK} = 2.6V$	$T_{amb} = 70^\circ C$	0.2	0.33	mA	
		$T_{amb} = 0^\circ C$		0.33		0.5
	$V_{CLK} = 1V$	$T_{amb} = 70^\circ C$		125	μA	
I_{EN} Enable input current	$V_{EN} = 2.6V$	$T_{amb} = 70^\circ C$	0.2	0.33	mA	
		$T_{amb} = 0^\circ C$		0.33		0.5
	$V_{EN} = 1V$	$T_{amb} = 70^\circ C$		125	μA	
R_{IN} Input pull-down resistance	Clock input	$T_{amb} = 25^\circ C$ $V_{CLK} < V_s$		8	K Ω	
	Enable input	$T_{amb} = 25^\circ C$ $V_{EN} < V_s$		8		
	Data input	$T_{amb} = 25^\circ C$ $V_{DI} < V_s$		4.5		
V_{DO} Output logic levels (pin 7)	Low state (L) $V_{DI} = 0V$	$I_{DO}(\text{pin } 7) = 0$		0.01	0.5	V
	High state (H) $V_{DI} = 2.6V$ $I_{DO}(\text{pin } 7) = -0.75$ mA		2.6	3.4	V	
R_{DO} Output pull-down resistance (pin 7)	$V_{DI} = 0V$ $V_{DO} = 1V$		14		K Ω	

* Pulsed; pulse duration = 300 μs , duty cycle = 2%

ELECTRICAL CHARACTERISTICS (see fig. 1 and the section "definition of terms")

Parameter	Test conditions	Min.	Typ.	Max.	Unit
Clock, data and enable input	t_{CLK}	4			μs
	$\overline{t_{CLK}}$	5.5			
	t_{SET-UP}	1			
	t_{HOLD}	3			
Clock to enable delay	$t_{CLK EN}$	$2 t_{BIT}$			
Enable to clock delay	$t_{EN CLK}$	t_{BIT}			
Data output delay	t_{PDH}, t_{PDL}	$R_L = 5K\Omega, C_L \leq 10 pF$	0.8	2.5	μs
Output delay	t_{PDEL}		3		μs
	t_{PDEH}		3.5		
Output rise time		$R_L = 100 \Omega, C_L < 100 pF$	1.2		μs
Output fall time		$R_L = 100 \Omega, C_L < 100 pF$	1.2		μs
V_{DO} rise time			0.4		μs
V_{DO} fall time			0.4		μs

DEFINITION OF TERMS

- V_{SS} : External power supply voltage. The return for open-collector relay driver outputs.
- V_{DI}, V_{CLK}, V_{EN} : The voltages at the data, clock and enable inputs respectively.
- V_{DO} : The voltage at data output.
- t_{BIT} : Period of the incoming clock.
- t_{CLK} : The portion of t_{BIT} when $V_{CLK} \geq 2.6V$.
- $\overline{t_{CLK}}$: The portion of t_{BIT} when $V_{CLK} \leq 0.8V$.
- t_{HOLD} : The time following the start of t_{CLK} required to transfer data within the shift register.
- t_{SET-UP} : The time prior to the end of $\overline{t_{CLK}}$ required to insure valid data at the shift register input for subsequent clock transitions.